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(12) **United States Design Patent**  
**Bauman**

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(54) **ELECTRICAL TEST PROBE**

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(US)

(\*\*) Term: **14 Years**

(21) Appl. No.: **29/121,319**

(22) Filed: **Apr. 6, 2000**

(51) **LOC (7) Cl.** ..... **10-04**

(52) **U.S. Cl.** ..... **D10/78**

(58) **Field of Search** ..... D10/78; 324/72.5,  
324/149, 156, 508, 509, 538; 340/815.74

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

D. 344,681	*	3/1994	Nightingale et al.	.....	D10/78
D. 389,419	*	1/1998	Beha	.....	D10/78
4,139,817	*	2/1979	Boer et al.	.....	324/72.5
5,414,346	*	5/1995	Mohan	.....	324/72.5
5,541,564	*	7/1996	Climar et al.	.....	324/73.5 X

\* cited by examiner

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(57) **CLAIM**

The ornamental design for an electrical test probe, as shown and described.

**DESCRIPTION**

FIG. 1 is a perspective view of the electrical test probe of this invention showing a detachable primary probe point detached to reveal a non-detachable secondary sharp probe point;

FIG. 2 is a top view thereof with the secondary probe point covered;

FIG. 3 is a top view thereof to clearly illustrate the location of views shown in FIGS. 8, 9 and 10;

FIG. 4 is a front view thereof with the secondary probe point covered, the back view being a mirror image of the front view;

FIG. 5 is a bottom view thereof with the secondary probe point covered;

FIG. 6 is a left side view thereof;

FIG. 7 is a right side view thereof;

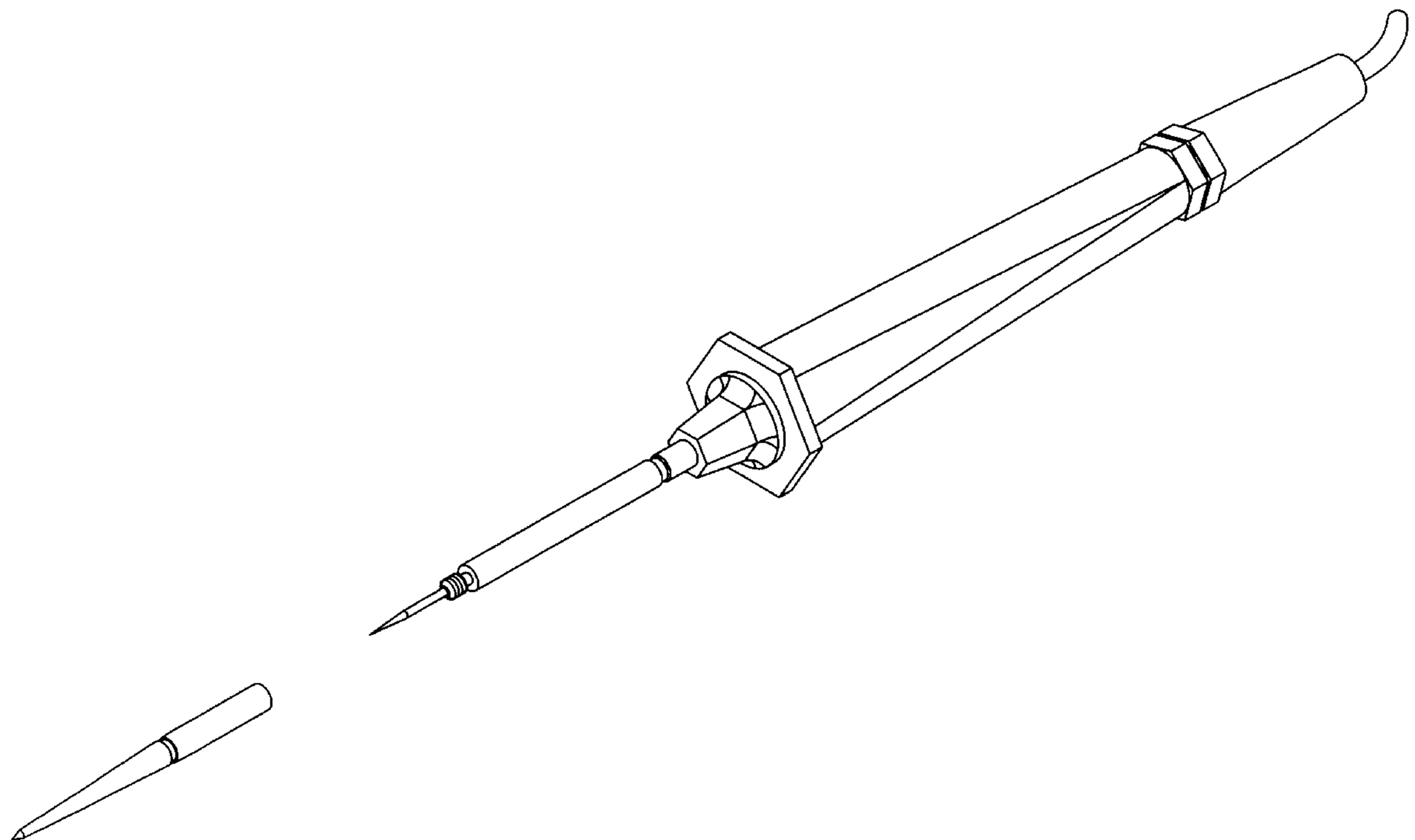
FIG. 8 is a view of the exterior surfaces only of what would be seen were the probe cut and viewed along the line 8—8;

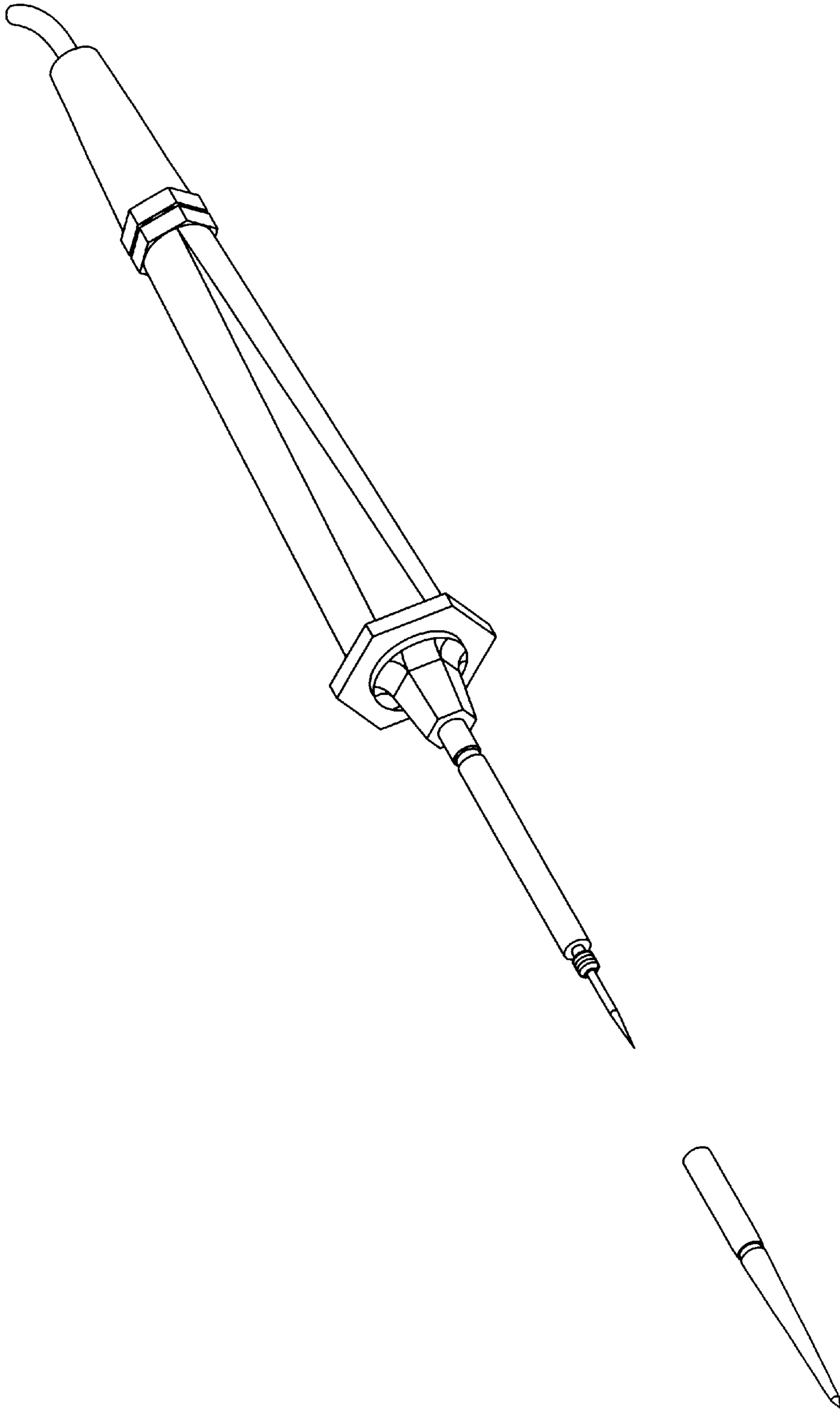
FIG. 9 is a view of the exterior surfaces only of what would be seen were the probe cut and viewed along the line 9—9;

and,

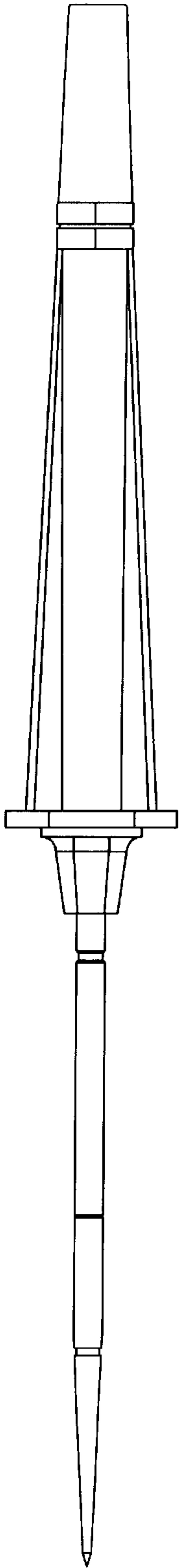
FIG. 10 is a view of the exterior surfaces only of what would be seen were the probe cut and viewed along the line 10—10.

**1 Claim, 3 Drawing Sheets**

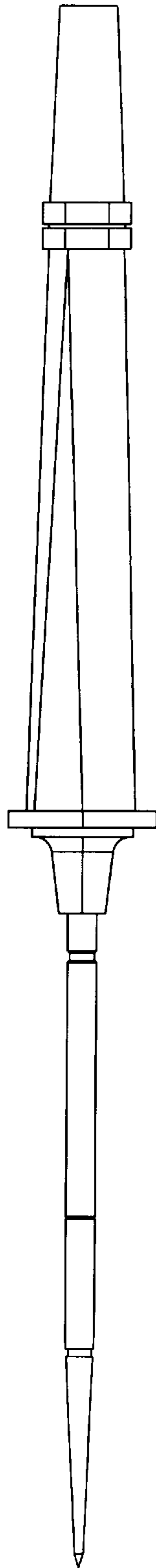




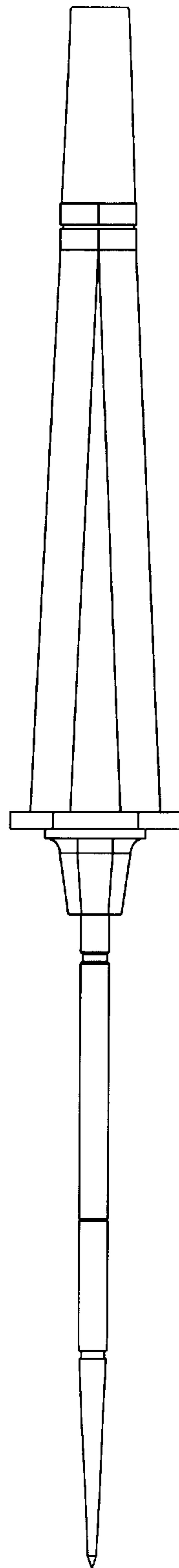
**Fig. 1**



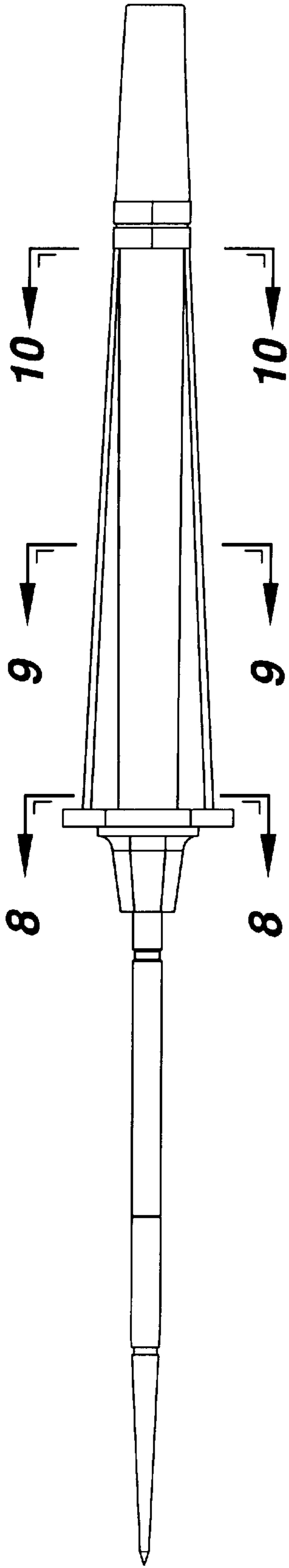
**Fig. 2**



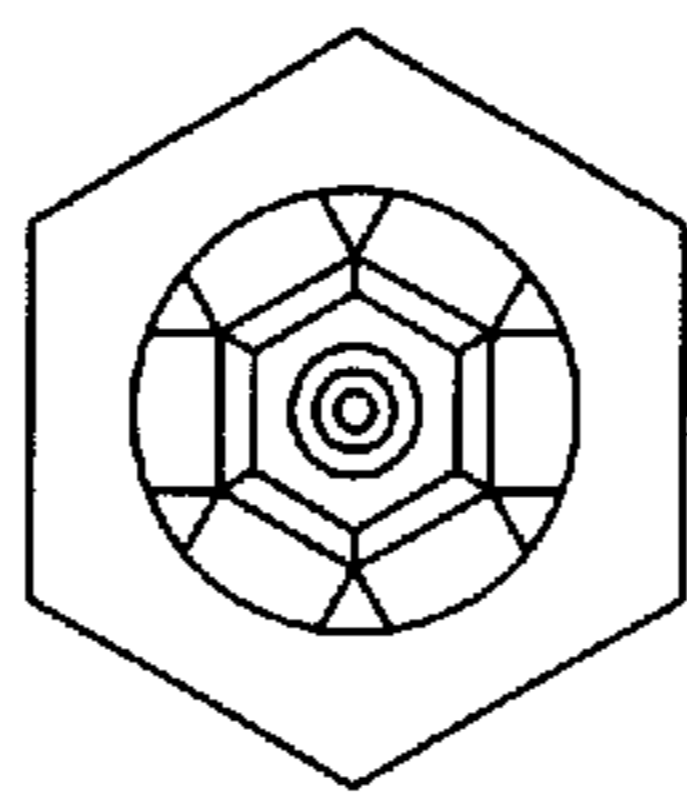
**Fig. 4**



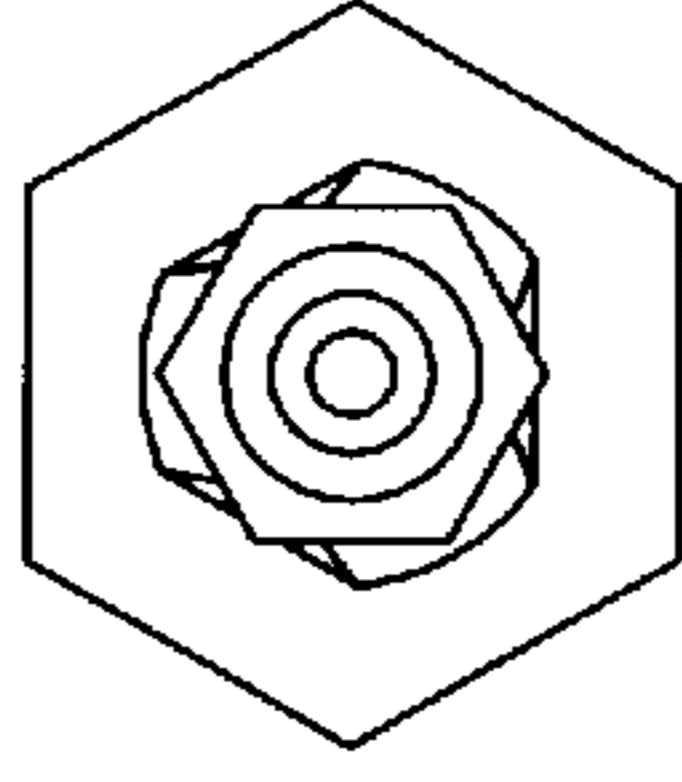
**Fig. 5**



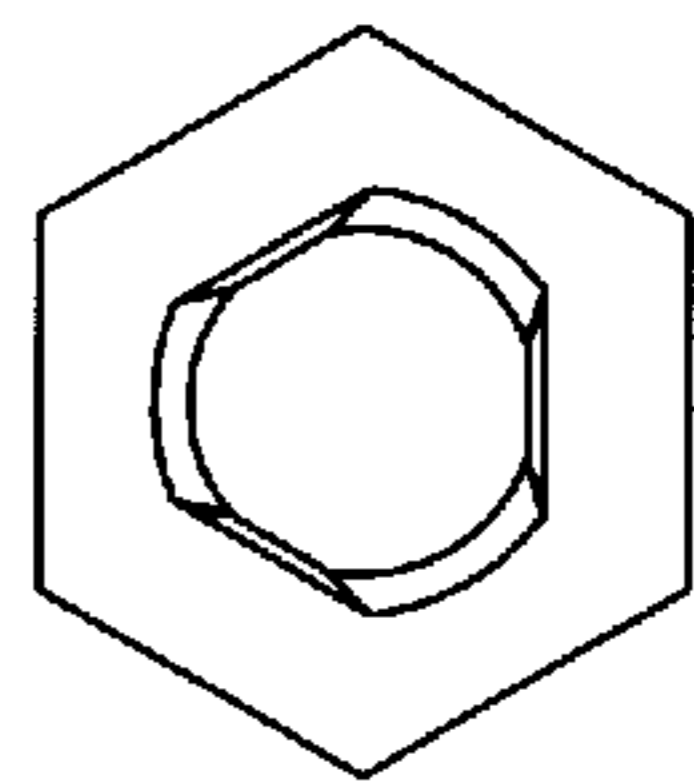
**Fig. 3**



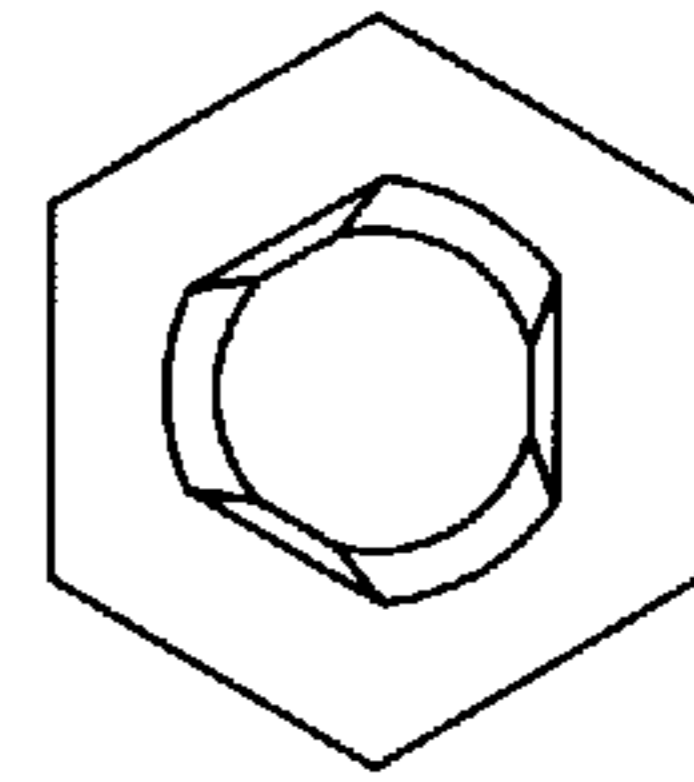
**Fig. 6**



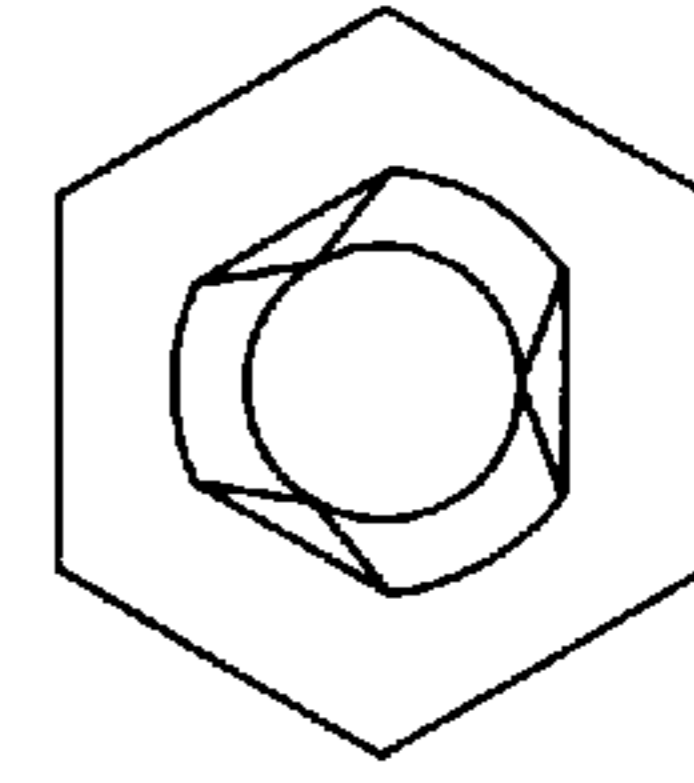
**Fig. 7**



**Fig. 8**



**Fig. 9**



**Fig. 10**